	Application/Control No.	Applicant(s)/Patent Under Reexamination
Issue Classification	10561730	CHO ET AL.
	Examiner	Art Unit
	Wiehe, Nathan	3745

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		Examiner		Art Unit		
		Wiehe, Nathan		3745		
	ORIGINAL		INTE	RNATIONAL	INTERNATIONAL CLASSIFICATION	
	CLASS	SUBCLASS	CLAIMED		NON-CI	NON-CLAIMED
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	CROSS REFERENCE(S)	ENCE(S)				
CLASS	SUBCLASS (ONE	SUBCLASS (ONE SUBCLASS PER BLOCK)				
415	220					
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Nathan Wiehe	Nathan Wiehe				Total Claim	Total Claims Allowed:
(Assistant Examiner)	niner) (Date)				-7	5
Keoger	tc/t/8 /27	EDWARD K. LOOK SIIPFRVISORY PATENT EXAMINER	Eles	John John John John John John John John	O.G. Print Claim(s)	O.G. Print Figure
(Legal Instruments Examiner)	ints Examiner) (Date)	(Primary Examine TECHNOLOGY CENTER 3700	(Date)	3/3/07	80	භ

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